



## 800V N-Channel MOSFET

Lead Free Package and Finish

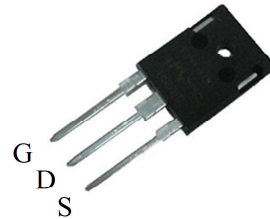
### General Features

- Advanced Planar Process
- $R_{DS(ON),typ.}=280\text{ m}\Omega@V_{GS}=10\text{V}$
- Low Gate Charge Minimize Switching Loss
- Rugged Poly silicon Gate Structure

$BV_{DSS}$	$R_{DS(ON),typ.}$	$I_D$
800V	280m $\Omega$	27A

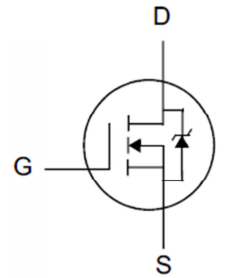
### Applications

- BLDC Motor Driver
- Electric Welder
- High Efficiency SMPS



TO-247

Package Not to Scale



### Ordering Information

Part Number	Package	Brand
PTF27N80	TO-247	

### Absolute Maximum Ratings

$T_C=25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Maximum Rating	Unit
$V_{DSS}$	Drain-to-Source Voltage	800	V
$V_{GSS}$	Gate-to-Source Voltage	$\pm 30$	
$I_D$	Continuous Drain Current	27	A
	Continuous Drain Current @ $T_C=100^\circ\text{C}$	17	
$I_{DM}$	Pulsed Drain Current at $V_{GS}=10\text{V}^{[2,4]}$	108	
$E_{AS}$	Single Pulse Avalanche Energy	4200	mJ
$dv/dt$	Peak Diode Recovery $dv/dt^{[3]}$	5.0	V/ns
$P_D$	Power Dissipation	650	W
	Derating Factor above $25^\circ\text{C}$	5.20	W/ $^\circ\text{C}$
$T_L$ $T_{PAK}$	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	300 260	$^\circ\text{C}$
$T_J$ & $T_{STG}$	Operating and Storage Temperature Range	-55 to 150	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

### Thermal Characteristics

Symbol	Parameter	Maximum Rating	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.192	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	55	



## Electrical Characteristics

### OFF Characteristics $T_J = 25^\circ\text{C}$ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$BV_{DSS}$	Drain-to-Source Breakdown Voltage	800	--	--	V	$V_{GS}=0V, I_D=250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	--	--	5	$\mu A$	$V_{DS}=800V, V_{GS}=0V$
		--	--	125		$V_{DS}=640V, V_{GS}=0V, T_J=125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Leakage Current	--	--	+100	$nA$	$V_{GS}=+30V, V_{DS}=0V$
		--	--	-100		$V_{GS}=-30V, V_{DS}=0V$

### ON Characteristics

$T_J = 25^\circ\text{C}$  unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	280	350	$m\Omega$	$V_{GS}=10V, I_D=13.5A$
$V_{GS(TH)}$	Gate Threshold Voltage	2.5	--	4.5	V	$V_{DS}=V_{GS}, I_D=250\mu A$
$g_{FS}$	Forward Transconductance	--	18	--	S	$V_{DS}=25V, I_D=12A$

### Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$C_{iss}$	Input Capacitance	--	7300	--	$pF$	$V_{GS}=0V, V_{DS}=25V, f=1.0MHz$
$C_{rss}$	Reverse Transfer Capacitance	--	33	--		
$C_{oss}$	Output Capacitance	--	650	--		
$Q_g$	Total Gate Charge	--	180	--	$nC$	$V_{DD}=400V, I_D=13A, V_{GS}=0 \text{ to } 10V$
$Q_{gs}$	Gate-to-Source Charge	--	40	--		
$Q_{gd}$	Gate-to-Drain (Miller) Charge	--	60	--		

### Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(ON)}$	Turn-on Delay Time	--	55	--	$nS$	$V_{DD}=400V, I_D=13A, V_{GS}=10V, R_G=10\Omega$
$t_{rise}$	Rise Time	--	100	--		
$t_{d(OFF)}$	Turn-Off Delay Time	--	80	--		
$t_{fall}$	Fall Time	--	95	--		



## Source-Drain Body Diode Characteristics

$T_J=25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Unit	Test Conditions
$I_{SD}$	Continuous Source Current <sup>[2]</sup>	--	--	27	A	Integral PN-diode in MOSFET
$I_{SM}$	Pulsed Source Current <sup>[2]</sup>	--	--	108		
$V_{SD}$	Diode Forward Voltage	--	--	1.5	V	$I_S=27\text{A}$ , $V_{GS}=0\text{V}$
trr	Reverse recovery time	--	900	--	ns	$V_{GS}=0\text{V}$ , $I_F=27\text{A}$ , $di_F/dt=100\text{A}/\mu\text{s}$
Qrr	Reverse recovery charge	--	2.0	--	uC	

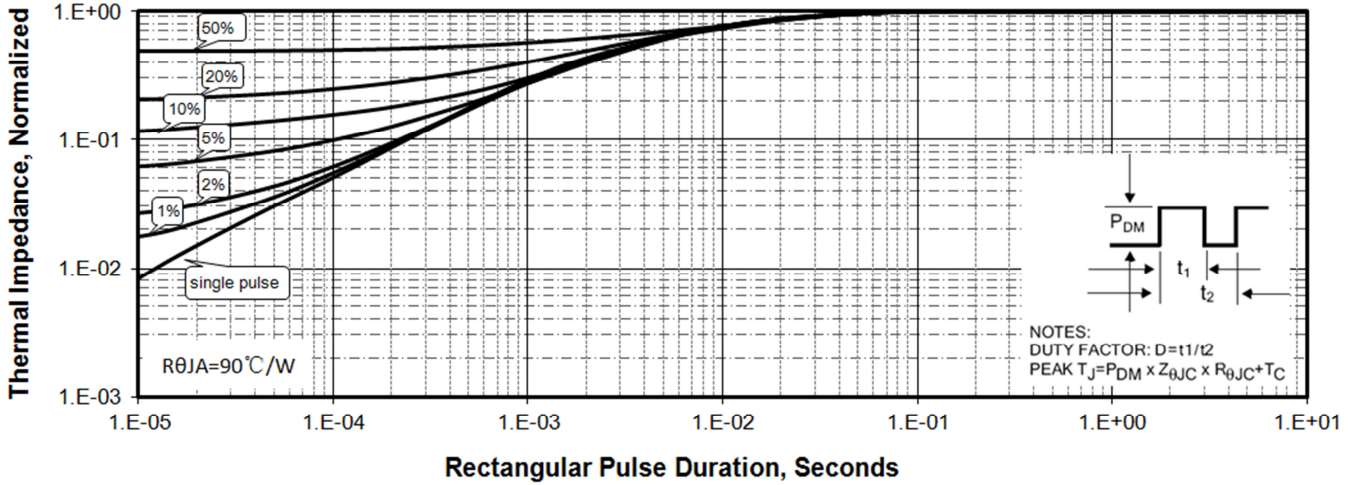
### Note:

- [1]  $T_J=+25^{\circ}\text{C}$  to  $+150^{\circ}\text{C}$  .
- [2] Silicon limited current only.
- [3] Package limited current.
- [4] Repetitive rating; pulse width limited by maximum junction temperature.
- [5] Pulse width $\leq 380\mu\text{s}$ ; duty cycle $\leq 2\%$ .

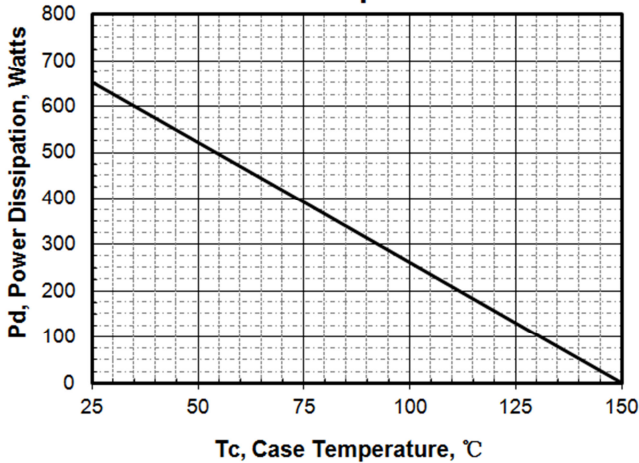


## Typical Characteristics

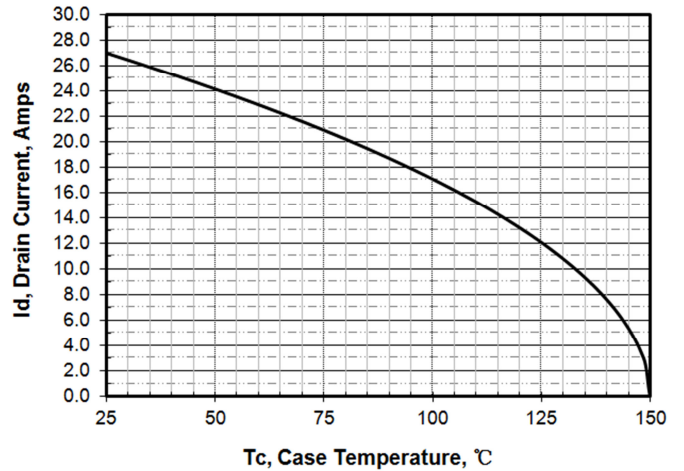
### Figure 1. Maximum Transient Thermal Impedance



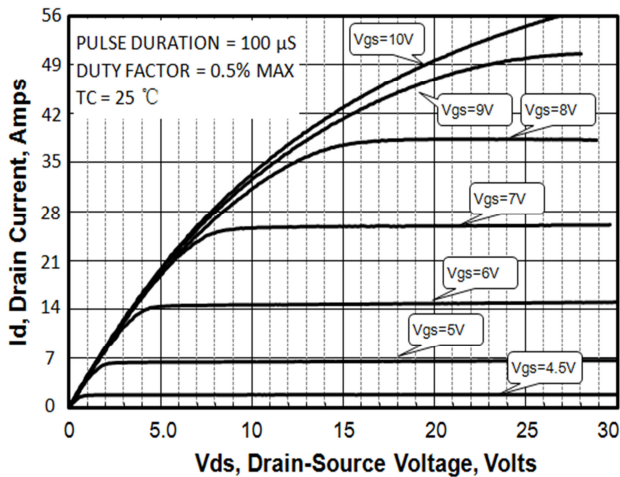
### Figure 2 . Max. Power Dissipation vs Case Temperature



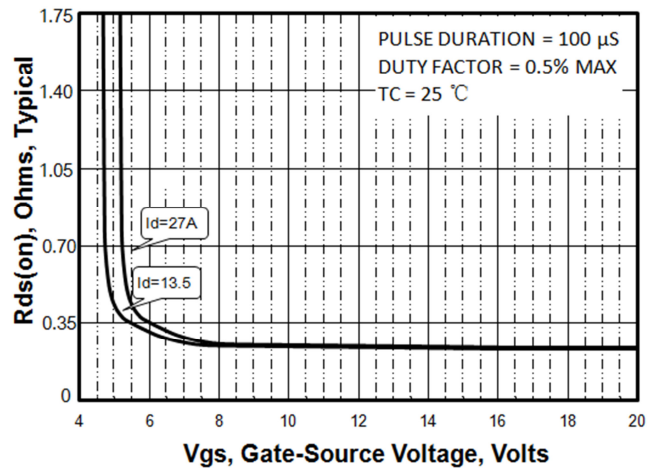
### Figure 3 .Maximum Continuous Drain Current vs Tc



### Figure 4. Output Characteristics



### Figure 5. Rds(on) vs Gate Voltage

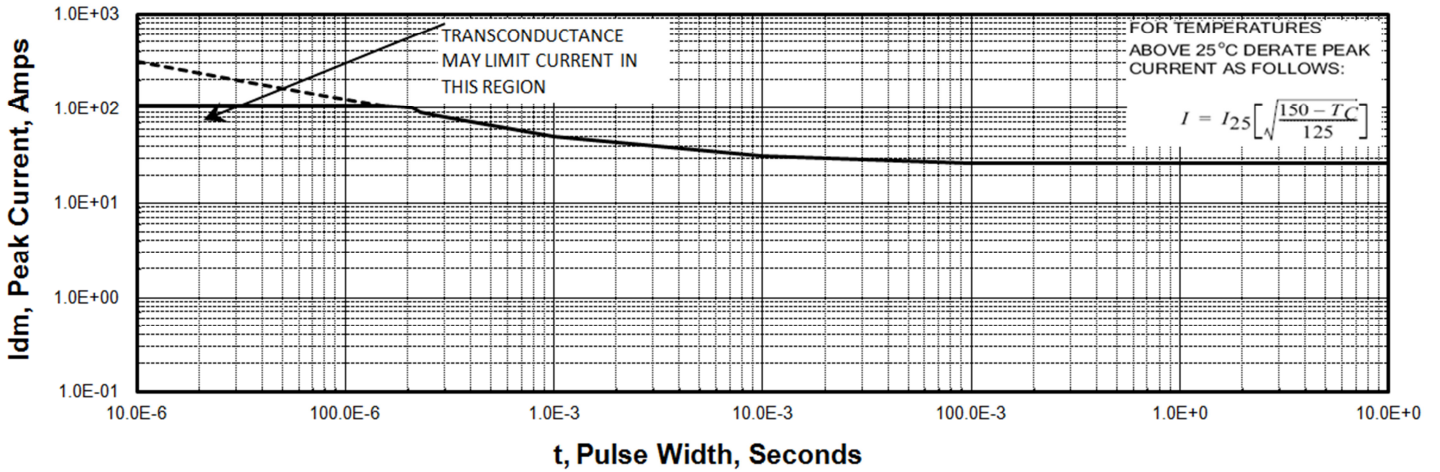




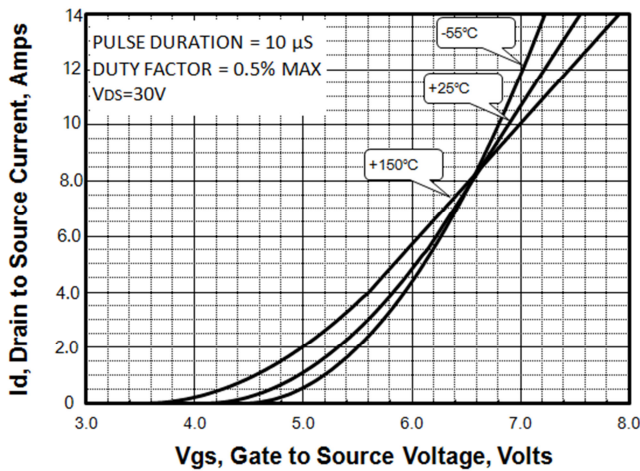


### Typical Characteristics(Cont.)

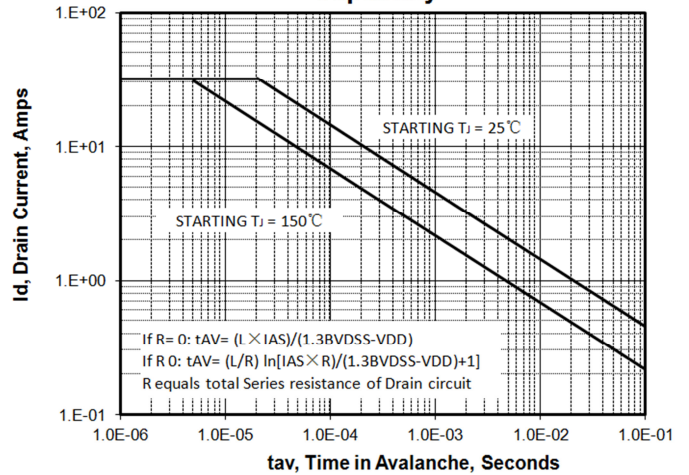
#### Figure 6. Peak Current Capability



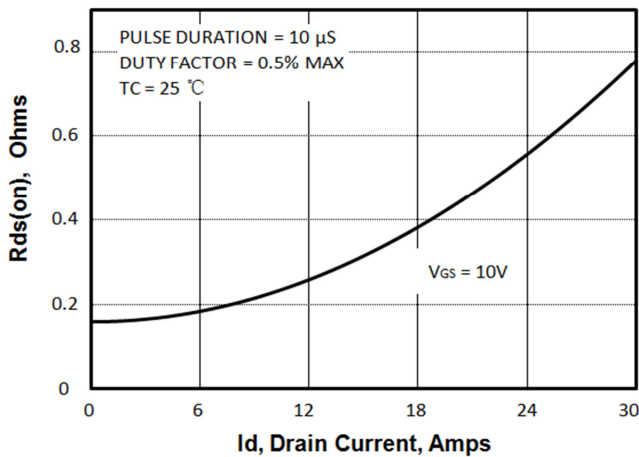
#### Figure 7. Transfer Characteristics



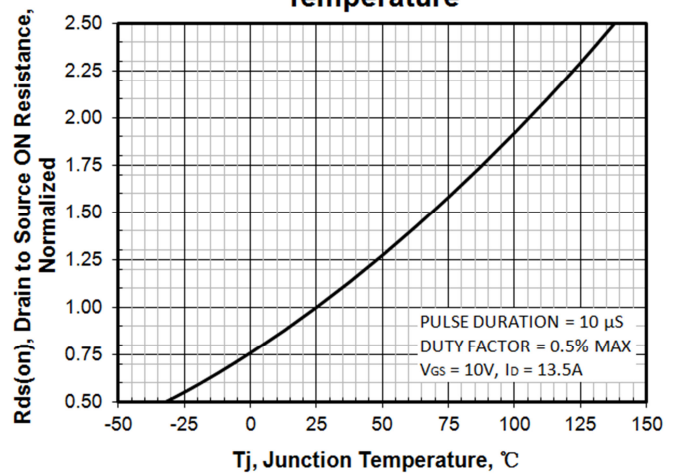
#### Figure 8. Unclamped Inductive Switching Capability



#### Figure 9. Drain to Source ON Resistance vs Drain Current



#### Figure 10. Rds(on) vs Junction Temperature





Typical Characteristics(Cont.)

Figure 11. Breakdown Voltage vs Temperature

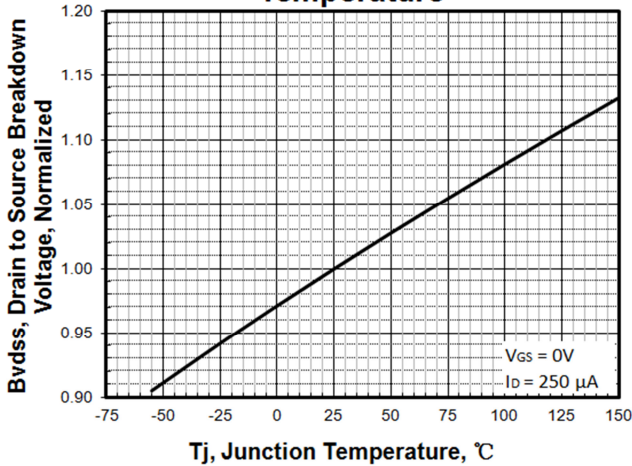


Figure 12. Threshold Voltage vs Temperature

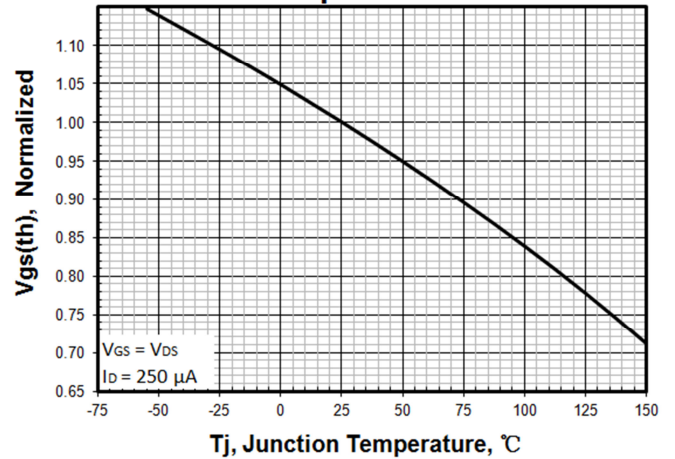


Figure 13. Maximum Safe Operating Area(TO-220F)

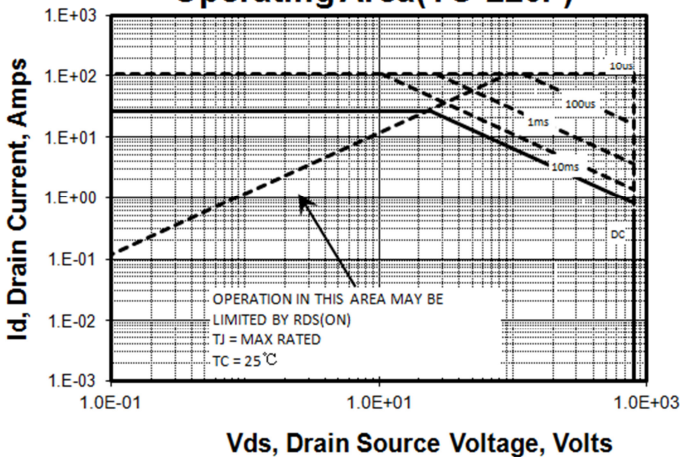


Figure 14. Capacitance vs Vds

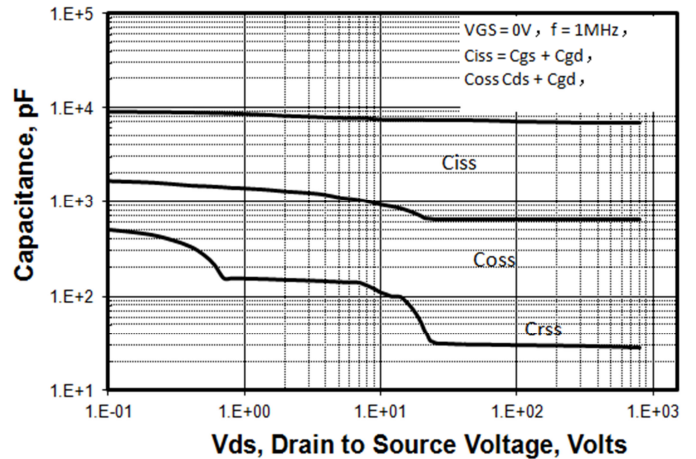


Figure 15. Typical Gate Charge

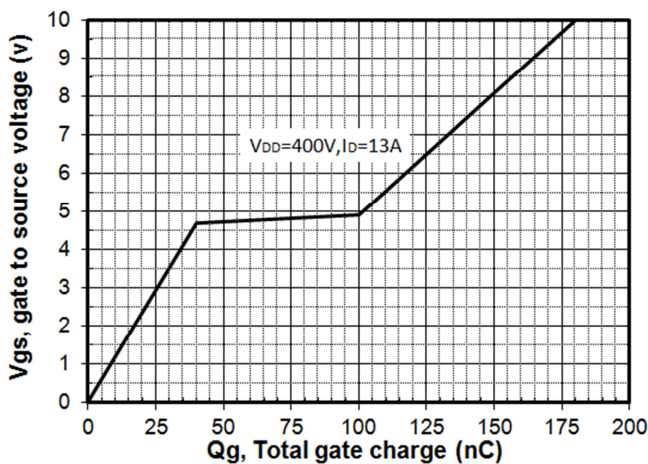
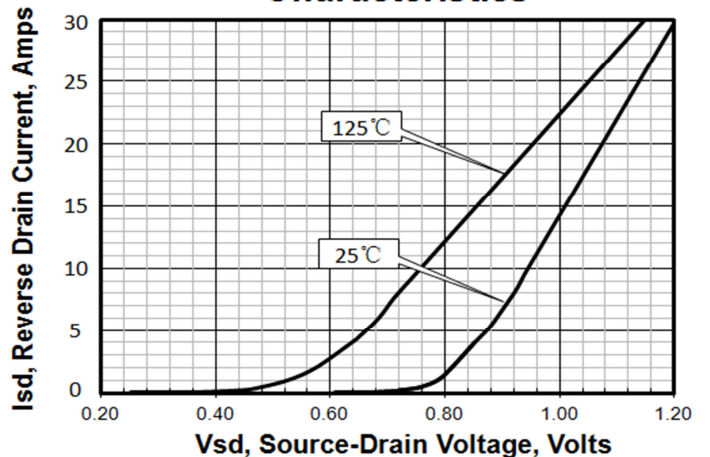


Figure 16. Body Diode Transfer Characteristics



Test Circuit Waveforms

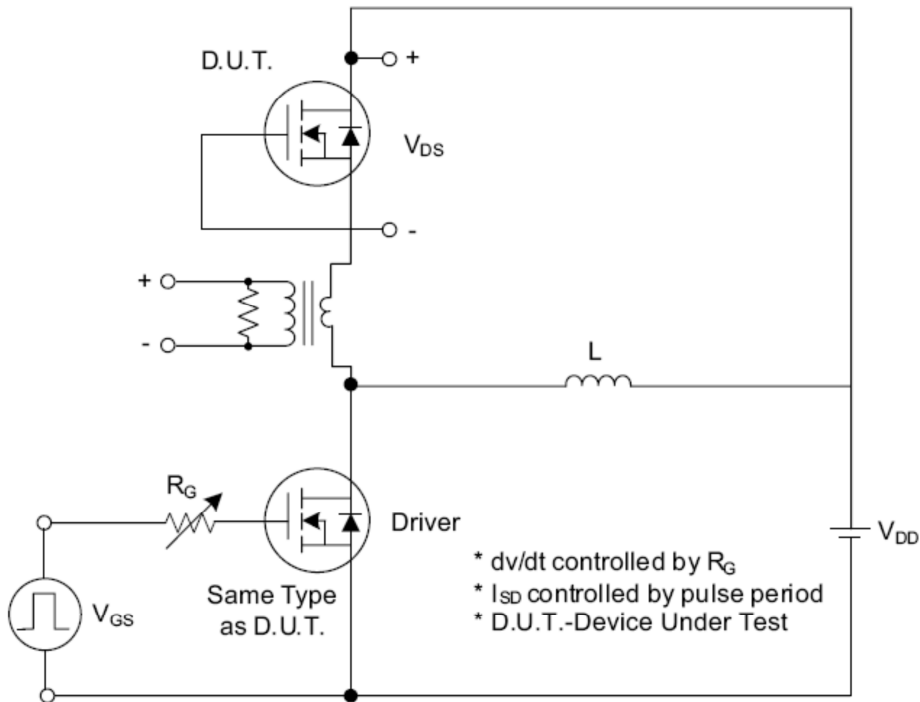


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

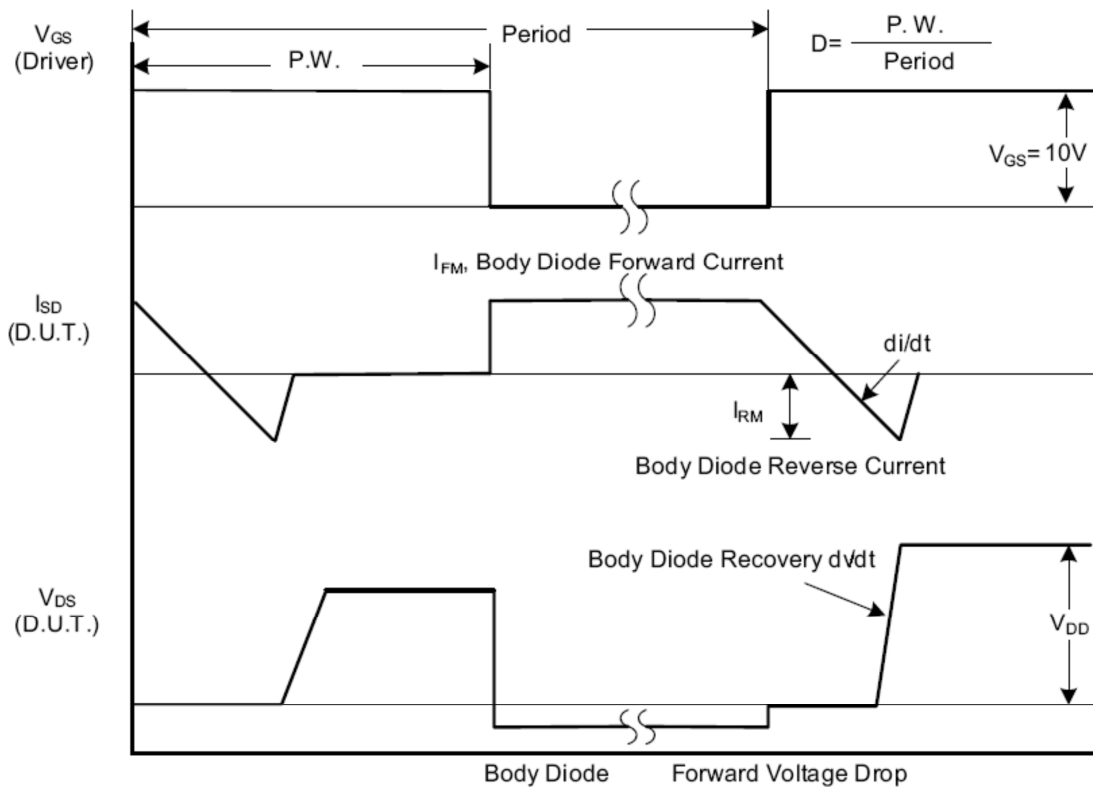


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

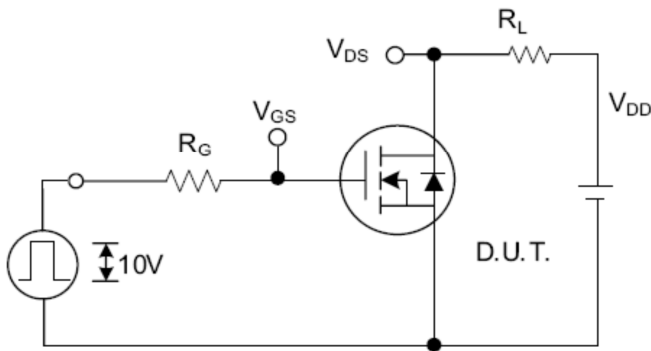
**Test Circuits and Waveforms (Cont.)**

Fig. 2.1 Switching Test Circuit

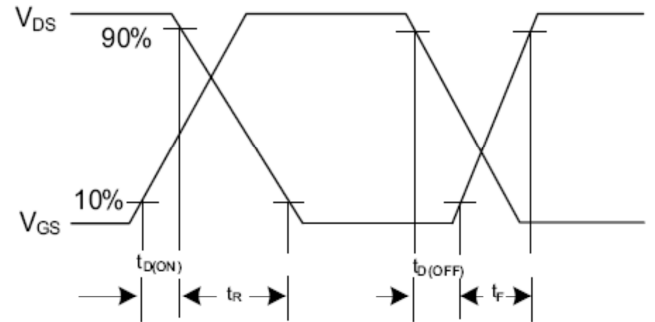


Fig. 2.2 Switching Waveforms

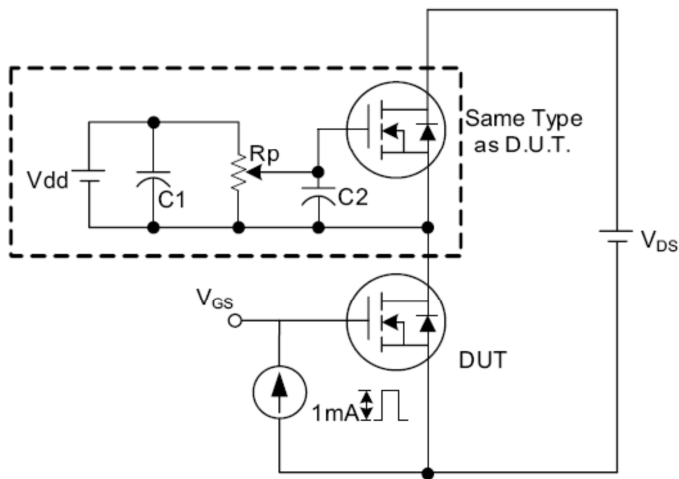


Fig. 3.1 Gate Charge Test Circuit

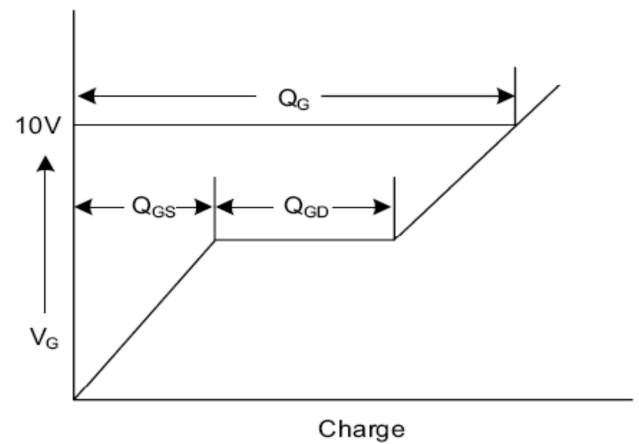


Fig. 3.2 Gate Charge Waveform

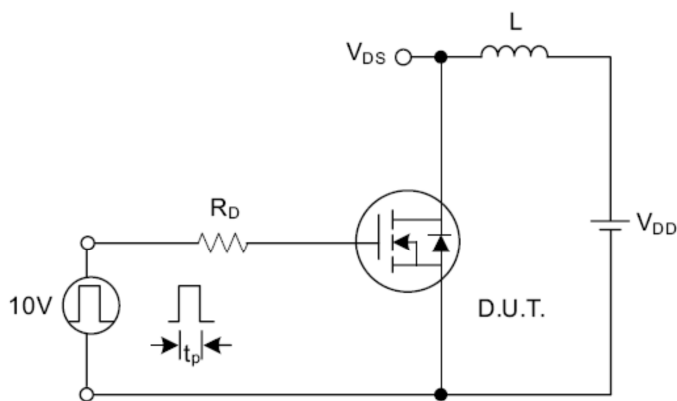


Fig. 4.1 Unclamped Inductive Switching Test Circuit

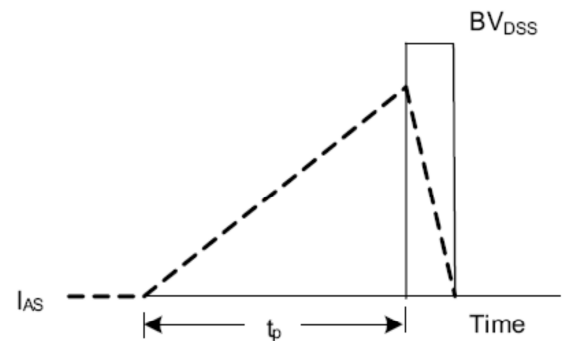


Fig. 4.2 Unclamped Inductive Switching Waveforms



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